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Exploring natural and artificial materials design using micron-scale structure and strain mapping

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Exploring natural and artificial materials design using micron-scale structure and strain mapping

The availability of sub-micron focused synchrotron X-ray beams has opened up exciting opportunities for understanding the internal architecture and deformation behaviour of intricately structured natural and artificial materials.

In recent years we have looked at a wide range of systems that range from human dental tissues to flax fibres to thermoplastic polyurethanes to carbon fibres and aerospace alloys and composites.

The unifying theme in our studies is the interest in strain:

How does it manifest itself at different scales?

How can it be reconstructed in all its complexity of multiple components and spatial variation?

How do we overcome the decade-old **d**₀ problem?

Answers will be provided using examples from recent research.



Exploring natural and artificial materials design using micron-scale structure and strain mapping

STRAIN -

the ultimate frontier...



continuum mechanics constitutive behaviour defect dynamics dislocations, grain boundaries, phase distribution atomistic dynamics, quantum mechanics core effects, chemical sensitivity Structure levels



Stresses and strains in polycrystals





Combustion Liners





EBSD map of IN718



11.0

Anisotropic 3D polycrystalline plasticity



Microstructure is generated to match texture and grain size + assumed to be periodic. Grain boundaries are smeared out (orientation set at Gauss points).







Cyclic stress-strain behaviour of grain sub-ensembles



Elastic strain (x10⁶)

B16: micro-beam Laue



- White beam (5-25keV) focused or collimated to spotsize < grainsize
- Illuminate gauge
 volume within single
 grain
- Lattice planes with H_{hkl} in the permissible q range diffract and give rise to diffraction spots on the detector
- Collect large number of spots in one shot



Laue Spot evolution



- Laue Spot evolution in different grains confirms the Schmid factor prediction
- Breaking up of Laue spots with deformation makes indexation difficult
- For streaked spots fitting with a more appropriate function than a 2D Gaussian might help



Scanning X-ray micro-beam topography

Full grain white beam topograph

(A)



384

401

Scanning micro-beam diffraction topography

•Composed of individual micro topographs, positioned with CoG according to motor position

•Reveals sub-pixel lattice mis-orientation



Abbey B, Korsunsky AM et al (2011) Scripta Mater.

Scanning X-ray micro-beam topography



- Clearly visible regions of high and low rotation gradient agree with slip systems
- Rotation gradient agrees well with FWHM
- FWHM shows power-law variation with sample dimension similar to Hall-Petch
- Suggests that dislocations become trapped and pile up at boundary



Abbey et al., 2012

Abbey B, Korsunsky AM et al (2011) Scripta Mater.





Salvati E., Korsunsky AM et al (2015) Crack Paths conference (Ferrara)

Electron Back Scatter Diffraction (EBSD)

- Sample positioned at an angle of 70°
- 1. Focused electrons interact with regular atomic structure (lattice)
- 2. Kikuchi diffraction patterns produced
- 3. Patterns detected and recorded
- Angle and shape of patterns used to gain information on material\
- Inter- & intra-granular analysis of
 - Orientation
 - Size
 - Phase
 - Dislocation density + type
 - Stress ? ...needs reference!







The FIB ring-core and DIC Technique

- In-plane residual stress determination
- 1. Region of interest is located on FIB and Scanning Electron Microscope (SEM)
- 2. Micrograph captured using SEM
- 3. Small increment of a ring-core milled into surface
 - Careful balance of material dependent parameters to produce effective milling shape
- 4. Second SEM image captured
- 5. Process repeated until large depth (approx. equal to core diameter) is reached



FIB and SEM directed at same

position on sample surface



Video of resulting SEM images



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Strain Relief of micro pillar

- Core approaches fully stress-relieved state
 - Core-size defines resolution of the analysis technique – typically in the range 0.5-20µm
- SEM images provide a record of the surface relaxation as a function of milling depth
- Digital Image Correlation (DIC) provides evaluation of displacement and strain relief
- Surface quality and contrast is key to effective DIC:
 - High resolution imaging required
 - Re-deposition of material must be minimised
 - Intrinsic surface roughness may be used for contrast
 - e-CVD marker deposition helps improve contrast



Rough surfaces can be provide sufficient contrast for DIC



Electron deposition patterning is necessary on untextured surfaces



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Digital Image Correlation (DIC)



1. Collection of SEM images



2. Place markers onto core surface and run automated DIC scripts



 Outlier removal of poorly tracked markers



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Complete strain relief estimation

- Least squares fitting, allowing for variation in the material removal rate and start depth (influenced by surface roughness)
- Signal to noise ratio dependent upon specific implementation





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Nano-scale mapping of lattice strain and orientation inside carbon core SiC fibres by synchrotron X-ray diffraction

- Cross validation with high resolution XRD
- Aerospace composite
 - Titanium alloy (Ti-6Al-4V) matrix
 - Unidirectional SiC fibres
 - Carbon monofilament core
 - C-inner and C-outer layers
- Built-in elastic strain structural integrity
 - C core + SiC shell
 - Manufacturing amd processing optimisation



SiC fibres with carbon monofilament core



N. Baimpas, A.M. Korsunsky et al., Carbon, 2014

SXM

• High resolution (~200nm step) line scans in SiC shell and carbon core



SiC coating

Carbon monofilament



N. Baimpas, A.M. Korsunsky et al., Carbon, 2014

Strain profiles





N. Baimpas, A.M. Korsunsky et al., Carbon, 2014

Absolute stress evaluation



UNIVERSITY OF OXFORD

N. Baimpas, A.M. Korsunsky et al., Carbon, 2014

C-SiC fibre – internal stress state

UNIVERSITY OF



N. Baimpas, A.M. Korsunsky et al.,

Carbon, 2014

Carbon monofilament (~35um diameter)

- Crystalline volume fraction variation (V_c)
- Crystalline aspect ratio variation (Size of markers)
- Absolute strain variation inside the fibre Eigenstrain modelling





N. Baimpas, A.M. Korsunsky et al., Carbon, 2014

Multi-scale nature of strain in a thermoplastic polyurethane (TPU)

✤ A two-phase microstructure at the nm-scale



By courtesy of Dr Kayleen Campbell, University of Queensland

TEM illustration of polymer nanostructure and a schematic diagram of the hard-soft segment structure.



Experimental Techniques



Figure 2: A schematic diagram of *in situ* cyclic tensile loading experimental setup.

Beamline:	Energy:	Beam size:
B16 (DLS, U.K.)	18 keV monochromatic	0.7×0.7 mm ²



Bringing it all together ...





How is that possible? ...looking to explain



P.R. Laity, et al. Polymer, 45, 2004





"Fuzzy" interfaces



(a)

(b)



Setting up the model





FEM





2D-FFT

Model validation - FFT



(b)



Multi-modal X-ray and FIB-SEM analysis of Li-ion batteries



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Layered LiMO₂ (M=Co, Ni, Mn)



Spinels LiMn₂O₄, Li₄Ti₅O₁₂



LiFePO₄



Graphite



Li₂Fe SiO₄



Layered-layered Composite



Cathode materials

MNC Li battery cathodes



High magnification SEM image of primary particles of active material that reveals the details of their morphology. Hexagonal habit platelets of oxides can be clearly recognised in the small stack to the top right of image centre, whilst elsewhere the multi-layer nature of the particles composed of laminae ~50 nm in thickness



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X-ray studies of Li-ion batteries: imaging, diffraction, XAS



normalized xm(E)

normalized xm(E)

Absorption Spectroscopy for the Characterisation of NMC oxides for Li-ion Battery Cathodes

T. Kim, et al., IMECS 2013









In situ Li-battery XRD





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Insights obtained

- Li diffusion is accompanied by changes in the chemical state of transition metals
- Lattice strains of the order of a few percent occur during lithium (de)intercalation
- The system is however highly inhomogeneous at the nanoscale: the relatively large beam (~70um) used in the experiment gives integral across the sample
- Local "hot spots" may lead to higher strains, causing fragmentation, loss of connectivity, and thus battery degradation and capacity fading
- What approach may reveal nano-scale inhomogeneity of Li+ migration?



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- FIB-SEM TOF-SIMS enables quantitative Li mapping in battery cathodes
- The ratio of Li concentration in discharged and charged states is ~ 4:1 (theoretical ~5:1)
- Li "trapped" at grain boundaries and particle-matrix interfaces



Tan Sui, A.M. Korsunsky et al. (2015) NanoEnergy

Particle fragmentation







A.M. Korsunsky, Tan Sui et al. (2015) Materials & Design

Fragmentation







Tan Sui, A.M. Korsunsky et al. (2015) J Materials Chemistry A

November 1, 2015

Fragmentation

Near the electrode/electrolyte interface



In the bulk of the electrode





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FIB serial sectioning for 3D vis of fragmentation





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